

PROTECTING POE PSE AND ETHERNET TO THE LATEST INTERNATIONAL OSP STANDARDS

Part 3 of 3

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Introduction



- Part 1 (ATIS-2015) Addressed field failures seen and was presented by Jim Wiese.
- Part 2 (ATIS-2015) covered protecting the PoE and Ethernet semiconductor IC's to make them more robust to the elements.
- Part 3 will provide an update and review of the latest ITU-T 04/2015 revision standards and address the periphery components not covered in part 2 such as the transformers and RJ-45 socket to make equipment pass the OSP standards.





 Let's look at what's forcing significant changes in Ethernet design. The most recent changes are coming from:-

International Telecommunication Union (ITU-T) K.20, K.45 & K.21 Revision 04/2015

ITU-T K.series Standards



• K.20 – Central Office

 Resistibility of telecommunications equipment installed in a telecom center to over voltages and over currents.

• K.45 – Remote Access

 Resistibility of telecommunications equipment installed in the access and trunk networks to over voltages and over currents.

• K.21 – Customer Premise

- Resistibility of telecommunications equipment installed in customer premises to over voltages and over currents.
- K.44 Test Support Document
 - Resistibility tests for telecommunication equipment exposed to over voltages and over currents – Basic recommendation.

2011 Ethernet Tests



- Testing Ethernet ports for ITU-T was almost non-existent....
 - K.45 Ethernet ports not tested.
 - K.20 internal ports longitudinal test.
 - 500 V basic, 1 kV enhanced.
 - K.21 internal ports longitudinal test.
 - 1000 V basic, 1.5 kV enhanced.
 - No transverse surges.
 - No PoE pair-pair port tests
 - There was an indication in K.44 test document that it was coming.

Rule of thumb was that if the port passed GR-1089-CORE intra-building, it also passed international testing.

Let's take a closer look at ITU-T 04/2015 released last year as lot's of NEW tests have been added!



External Ethernet Deployment

Table 2a – Lightning test conditions for ports connected to external symmetric pair cables

| Test no. | Test description | Test circuit and waveform (see figures in Annex A of [ITU-T K.44]) | Basic test levels (also see clause 7 of [ITU-T K.44]) | Enhanced test levels (also see clauses 5 and 7 of [ITU-T K.44]) | Number of tests | Primary protection [ITU-T K.44], clause 8) | Acceptance criteria [ITU-T K.44], clause 9) | Comments |
|---------------------|---|---|--|--|--|---|---|--|
| 2.1.7 <u>New</u> | UTP Ethernet transverse | Figure A.6.7-5 (1.2/50-8/20 combination wave generator (CWG)) R=10 Ω | U _{c(max)} = 600 V | U _{c(max)} = 1500 V | alternating ±5 surges (60 seconds between successive surges) | None | А | (lower voltage level testing also required – see clause 7.3 of [ITU-T K.44] |
| 2.1.8 | STP Ethernet simultaneous port to earth test | Figure A.6.7-4 (1.2/50-8/20 CWG) R=10 Ω | U _{c(max)} = 2500 V | U _{c(max)} = 6000 V | alternating ±5 surges (60 seconds between successive surges) | None | А | (lower voltage level testing also required – see clause 7.3 of [ITU-T K.44]) |
| 2.1.9 | UTP Ethernet port rated impulse voltage test | Figure A.6.7-3a (1.2/50-8/20 CWG) R=5 Ω | U _{c(max)} = 2500 V surge | U _{c(max)} = 6000 V | 2 of each polarity for surge/ single applicatio n for dc | None (Note 1) | A | There shall be no insulation breakdown during the test and the post test resistance shall be at least 2 M Ω when measured at 500 V d.c. |
| 2.1.10 | PoE Mode A & Mode B transverse testing | Figure A.6.7-2 (1.2/50-8/20 CWG) R= 10 Ω | $U_{c(max)} = 600 V$ | U _{c(max)} = 1500 V | Alternatin g ±5 surges (60 seconds between surges) | None | A | (lower voltage level testing also required – see clause 7.3 of [ITU-T K.44]) |

UTP = Unscreened Twisted Pair

STP = Screened Twisted Pair

A.6.7-5 Transverse Test



- Test # 2.1.7 external building
 - ITU-T Basic
 - 600 V 1.2/50 = 50 A.
 - ITU-T Enhanced
 - 1500 V 1.2/50 = 125 A.

GR-1089-CORE internal building tests with 800 V 1.2/50, 6 Ω (100 A).



GR-1089-CORE has been proven to solve field issues in the USA.



1, 2, 3, 4, 5, 6, 7 and 8 are Ethernet RJ45 pin numbers a = RJ45 screen cable connection for STP connections b = EUT protective or functional earth connection

b = EUT protective or functional earth connection c to d = Terminals of all other signal ports

NOTE - This test is conducted to each lead (1-8) separately connected to the generator one at a time, with all of the other leads grounded.



External Transverse Tests



There is no transverse test for SHIELDED
 EXTERNAL CABLES?



- Shielded cable don't protect against common-mode to differential surge events!
 - Isolation at the Jack to its shield or transformer breakdown?
 - One end using GDT surge protection to Earth?
 - Common to see OSP deployments with GDT primary protectors.

External Transverse Tests





- Arcing from conductor to Earth or an over-voltage protector is used on the interface.
 - Over-voltage protection (GDT's) are common for OSP interfaces.
- The question then comes down to what level of voltage can be seen across the cable shield during surge?

Shielded Cable Length





- Short cable length looks worse when surged across it!
 - 1.2/50-8/20 generator produced a lot higher surge than the 10/700 generator.
 - 6 kV surge is in the 2.5 kV region for 25ft of cable.
 - Inductance of the cable.
 - Found that using RJ-45 sockets at both ends typically increased the voltage by 15%.
 - Coiling the cable in a bundle typically added 25%.

External Ethernet



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| 2.1.10 | PoE Mode A & Mode B transverse testing | Figure A.6.7-2 (1.2/50-8/20 CWG) R= 10 Ω | U _{c(max)} = 600 V | U _{c(max)} = 1500 V | Alternatin g ±5 surges (60 seconds between surges) | None | A | (lower voltage level testing also required – see clause 7.3 of [ITU-T K.44]) |

UTP = Unscreened/unshielded twisted pair

STP = Screened/shielded twisted pair

A.6.7-4 Longitudinal Test



Test # 2.1.8 External Building.

- ITU-T Basic.
 - 2.5 kV 1.2/50, 208 A.
- ITU-T Enhanced.
 - 6 kV 1.2/50, 500 A.

Finally a 6 kV surge test for EXTERNAL Ethernet interfaces.





c to d = Terminals of all other signal ports



Great test for an isolated interface, but is the single conductor short circuit current enough if over-voltage protection is used on the interface?



External Ethernet



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| 2.1.10 | PoE Mode A & Mode B transverse testing | Figure A.6.7-2 (1.2/50-8/20 CWG) R= 10 Ω | U _{c(max)} = 600 V | U _{c(max)} = 1500 V | Alternatin g ±5 surges (60 seconds between surges) | None | A | (lower voltage level testing also required – see clause 7.3 of [ITU-T K.44]) |

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External Ethernet



Table 2a – Lightning test conditions for ports connected to external symmetric pair cables

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| 2.1.8 | STP Ethernet simultaneous port to earth test | Figure A.6.7-4 (1.2/50-8/20 CWG) R=10 Ω | U _{c(max)} = 2500 V Note that shielded done at the | U _{c(max)} = 6000 V | alternating ±5 surges (60 seconds between successive surges) | None | A ? "The | A of | | |
| 2.1.9 <u>New</u> | UTP Ethernet port rated impulse voltage test | Figure A.6.7-3a (1.2/50-8/20 CWG) R=5 Ω | U _{c(max)} = 2500 V surge | $U_{c(max)} = 6000 V$ | 2 of each polarity for surge/ single applicatio n for dc | 2 surges surge w Single a | s each polarity ithstand. pplication for d | | | |
| 2.1.10 | PoE Mode A & Mode B transverse testing | Figure A.6.7-2 (1.2/50-8/20 CWG) R= 10 Ω | U _{c(max)} = 600 V | U _{c(max)} = 1500 V | Alternatin g ±5 surges (60 seconds between surges) | None | A | ng also of | | |

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A.6.7-3a Isolation Test

- Test # 2.1.9 external building.
 - ITU-T Basic is at 2.5 kV.
 - ITU-T Enhanced is at 6 kV.
- Why is the "longitudinal" test different between unshielded and shielded cables?
- Very easy to protect against with an OV protector.
 - Might explain the 2x surges each polarity rather than 5x.
 - Would recommend a Hi-POT, 1s test at 80% of the peak surge voltages for <u>ALL</u> Ethernet interfaces instead.





External PoE



Table 2a – Lightning test conditions for ports connected to external symmetric pair cables

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| | | | Note that transverse tests are done at the same voltage. | | | and the same number of | | |
| | | | | | ſ | | | |
| 2.1.10 <u>New</u> | PoE Mode A & Mode B transverse testing | Figure A.6.7-2 (1.2/50-8/20 CWG) R= 10 Ω | $U_{c(max)} = 600 V$ | U _{c(max)} = 1500 V | Alternatin g ±5 surges (60 seconds between surges) | None | A | (lower voltage level testing also required – see clause 7.3 of [ITU-T K.44]) |

UTP = Unscreened/unshielded twisted pair

STP = Screened/shielded twisted pair

A.6.7-2 PoE Test

- Test # 2.1.10 external building
 - ITU-T Basic
 - 600 V 1.2/50 = 50 A.
 - ITU-T Enhanced
 - 1500 V 1.2/50 = 125 A.
 - GR-1089-CORE intra-building test with 800 V, 100 A (6Ω).
- This is a pair to pair test for the DC interface.
 - There are no pair-pair test for standard Ethernet ports?







External Shield Bond Test



Table 2a - Lightning test conditions for ports connected to external symmetric pair cables

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|----------------------|---|--|--|--|--|---|---|--|--|
| 2.1.11 <u>New</u> | STP Ethernet shield bond test | Figure A.6.7-6 (1.2/50-8/20 CWG) R=10 Ω | U _{c(max)} = 1500 V | U _{c(max)} = 6000 V | alternating ±5 surges (60 seconds between successive surges) | None | А | (lower voltage level testing also required – see clause 7.3 of [ITU-T K.44]) | |
| NOTE 1 study. | VOTE 1 – When the cabling is fitted with SPDs, the equipment user and manufacturer may use different test conditions upon mutual agreement; this topic is currently under tudy. | | | | | | | | |

STP = Screened/shielded twisted pair

A.6.7-6 Shield Bond Test

- Test 2.1.11 external building.
 - ITU-T Basic.
 - 1500 V 1.2/50, 25 A.
 - ITU-T Enhanced.
 - 6 kV 1.2/50, 500 A.
- GR-1089-CORE internal building test.
 - 1500 V, 375 A (2 Ω).



 Would the unshielded isolation test be correct if a shielded cable was used with an unshielded Jack?







Internal Building Changes



- What has changed for Internal building ports?
 - K.45 No tests in 11/2011 and nothing has been added in 04/2015.
 - Assumes the cable within the cabinet is very short and therefore no electrical stress?
 - K.21 Some additions.
 - K.20 Some additions but there are issues!

K.21 Intra-building Additions



Table 7 - Lightning test conditions for ports connected to internal cables



A.6.5-2 & A.6.7-4 Tests





• A.6.7-4 STP longitudinal Test







Table 7 – Lightning test conditions for ports connected to internal cables





K.20 Internal Cable "Blooper"

Table 7 - Lightning test conditions for ports connected to internal cables

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|-------------------|---|--|--|------|---|------|---|------------------|--------------------|--|---|----------|
| 7.4 | STP Ethernet simultaneous port to earth | Figure A.6.7-4 (1.2/50-8/20 CWG) R = 0 Ω | $U_{c(max)} = 100$ | 00 V | U _{c(max)} = 150 | 00 V | alternating ±5 surges (60 seconds between successive surges) | None | А | (lower voltage level testing also required – see clause 7.3 of [ITU-T K.44]) | | |
| | | | Note the discrepant shielded and unshielded and uns | | repancy between Inshielded cables? | | E | | | | | |
| | | | | | | , | T | | | | | |
| 7.6 <u>New</u> | UTP Ethernet port rated impulse voltage test | Figure A.6.7-3a (1.2/50-8/20-CWG) R = 5 Ω | U _{c(max)} = 250 surge | 00 V | U _{c(max)} = 600 surge | 00 V | 2 of each polarity/ single application of dc | None (Note 1) | A | There shall be no insulation breakdown during the test and the post test resistance shall be at least 2 M Ω when measured at 500 V d.c. | | |
| | | | | | | | | | | | | |



6 kV surge for an INTERNAL CABLE for a K.20 telecom center environment?

Looks like unshielded cables in the telecom center environment is not liked, but is this the **RIGHT** call?

International Standards Summary



- At last OSP Ethernet deployments have been recognized but....
 - Shielded twisted pair does not have a transverse test.
 - An Ethernet shielded cable is not a good protector against GPR's.
 - Shielded Ethernet cables don't make good earth straps.
 - 6 kV isolation test for K.20 internal Ethernet ports!
 - Isolation testing could be done with a single longitudinal test.
 - Internal building transverse for Ethernet is still missing.
 - Tests for shielded and unshielded ports should be the same.
 - No exclusions for very short (3 meter) outside building cabling.



 With the protection Bar set so high, lets look at the various components of PoE and Ethernet that need to be considered:-

PoE Controller Protection



- From last years presentation:-
- Consider blocking current rather than shunting the current around the FET.
 - Better results with a smaller package and lower cost component.
- Remove the capacitors that are connected between 48V_RTN and chassis GND.
 Be prepared to compromise with EMC!

Metallic Ethernet Solution



- Is clamping at the lowest voltage ideal?
 - Found that 2.8 V, 3.3 V options provide small gains if any and under-sized, but often command higher prices.
 - Difficult to do comparable data sheet comparisons between them.
 - The 5 V options are older product and often cheaper.
- 8/20 TVS diode surge current rating of 30 A.
 - Choosing a lower current option increases risk of failure.
 - Ports random failed with TVS diodes shorting with 10-15 A ratings.
 - One Manufacturer rates their TVS diode at 20 A, but their silicon design technique makes for a very robust solution.
 - Some standardization on dynamic electrical specifications would be nice.
- Steering diode Arrays seem to work well.

Metallic Ethernet Solution

• Requiring over-current protection is down to the PHY.

- Some PHY's can still be protected with just a 5V TVS diode but now a minority.
- Add over-current protection as a precaution.
- There are a range of options, but two seem to work well.
 - ECL (Electronic current limiter).
 - Very good protection but expensive.
 - Watch out for over-voltage stress if TVS diodes are not used.
 - Low value Resistor.
 - NO (if selected correctly) reduction in performance.
 - Allows 0Ω resistors to also be used.
 - Resistor (if selected correctly) has NO impact on line reach.
 - 1/16 Watt resistors are cheap as dirt.





Metallic Ethernet protection



- Ethernet transformers make excellent 1st level protectors.
 - Saturate early to limit secondary current.
 - Current let-through pulse is roughly 100 A 0.5/2 µs (delay to 50% of peak) type surge for intra-building to help set the tertiary protection.
 - TVS diode dynamic voltage clamp performance is important.
 - Act like a fuse with too much impulse current.
 - Good quality transformers usually achieve around 4 kV or more surge isolation between primary to secondary.
 - Not all transformers are made equal.
 - Watch out for multi-port components pin spacing for port-port.
 - Watch out for Engineering modifications to the wiring without a PCN.
 - Don't get caught out with wide manufacturing isolation tolerances.

Gotcha's



Measured Failure Thresholds of Ethernet Transformers

| Ethernet Transformer | Breakdown | Notes |
|----------------------|------------|------------------------|
| Wurth 7090-37 | 8 kV | |
| Wurth 7090-37 | 7 kV | |
| Falco LV2001 | 10 kV | |
| Pulse H1164 | Over 10 kV | |
| Halo TG110-RP26NY | Over 10 kV | |
| Pulse T1144 | 9 kV | |
| Pulse H1102 | 8 kV | |
| Pulse H2009 | 10 kV | |
| Pulse H5007NL | 5 kV | Second sample was 9 kV |
| | | |

ATIS PEG-2015, Randolph Telecom, Inc

- There is a wide tolerance due to micro-fracturing in the wiring enamel when wound on the bobbin and the inconsistency of the enamel thickness between different wire manufacturers.
- All the transformer manufacturers normally have to do is ensure 1500V RMS or 2250V DC Hi-POT.
- Grey area between the relationship between Hi-POT test and surge withstand capability.

Port to Port Spacing







Pad distance is just 0.38mm between the two pairs on this common dual port option. This is around 500 V isolation between port to port!

Port to Port Spacing Fix



- Added 3.8mm between ports with unused pins.
 - Would have liked more spacing, but the package would have to be changed.
 - Would have removed the benefit of footprint & cost.
 - A lead frame modification to remove the pins would help.
- What has been given up?





- No Bob Smith termination interfaces.
 - Remove all the problems associated with high voltage capacitors.
 - Design/layout ensures no EMC issues with this topology.
 - Saving on the B.S circuit allows focus in other areas for protection.



Longitudinal Ethernet Protection



- High voltage rated capacitors are required.
 - Meeting 6 kV surge withstand compounds the problem.
 - Makes the circuit expensive using 2x 3kV capacitors.
- Found not to impact EMC for Ethernet.
 - This is what Bob Smith was suppose to address!
 - Design and layout is important.



- Testing has not found EMC issues for PoE either.
 - Design and layout is important.



The savings on B.S circuit can be used for making POE interfaces more robust.



RJ-45 Integrated Jacks



Be cautious with integrated Jacks for Extended Isolation withstand performance.

- Lucky if they pass the IEEE-802 isolation withstand of 1500 V RMS or 2250 V DC.
- Transformers are in very small packages and often poor isolation.
- Internal spacing's to shield is also often limited.
- Stick with Jack-Only designs outside standard Ethernet interfaces.

RJ-45 Shielded Socket

 No exposed pins at the back of the unit, but arcing still occurred to the shield.

• Shield for EMC between top and bottom jacks.

• Arcing between the shield press fitting.









Metallic Ethernet protection

ADIRAN

- Solution was to remove the shields.
 - Worked very well for low port count applications.

.....but EMC got worried as this could cause an increase in eradiated emissions as there were six 4x2 modules (48 port) to create a nice large hole in the metalwork for some applications.

• Wrap the RJ-45 in Kapton tape under the shield!

.....there are still issues with the pin spacing's on the board but this needs a new module design.

Good news is that there seems to be experience in the jack manufacturer arena.



Integrated Sockets for Extended Surge Withstand



- Best option is to use just an RJ45 socket and place the magnetics on the board.
 - If there is space issue, anticipate isolation problems.
 - Seen integrated jacks specify that they pass the 1500V rms isolation tests but actually don't.
 - The sales Engineer's face was a picture!



- Seen integrated jacks that have <500 V of isolation
- Ones that do pass 2250 V DC often just make it!
 - Adtran now tests every Ethernet copper interface.

Example of an Integrated Jack

- Don't like showing the bad stuff, but this came across my desk one morning......
- First GDT only protecting the 75Ω resistors.
 - 75 Ω looks to be done to help coordination.
- Large currents will be seen in the transformer windings when the GDT operates.
- Will fail GR-1089-CORE 120 V RMS, 25 A power fault test as the wire simulator will operate when the first GDT operates.
- If GDT DC breakdown voltage's are above 2250 V DC to pass IEEE Hi-POT, the 2 KV cap or shield spacing is not suitably protected.
- GDT is probably set to pass the 500V dc isolation test for international testing.
-Conclusion?

This stuff CAN be made-up and it's out there!



PCB Layout for IEEE Isolation



• To meet IEEE 802 isolation requirements.

• 1500 Vrms, 2250 VDC, 1400 V 1.2/50 surge.



- 1 mm (40 mils) ~1 kV air isolation.
- Inner layer spacing of 0.5 mm (20 mils) ~1 kV internal isolation.

To Everything else

- Outside layer = 1.5 mm.
 - Often pushes traces to be on an inner layer.
 - Can cause layout errors at the connectors & transformers.
- Inside layer = 0.5 mm.
- Same port #
 - Outside layer = 0.3 mm
 - Matches typical pin-pin spacing of transformers.

PCB Layout to Exceed 6 kV



- 6 kV longitudinal surge, using the rule of thumb:-
 - Outside layer is increased to 6 mm.
 - Inside layer is increased to 3 mm.
 - Vertical plane between layers also comes into play.
 - Dependent on board thickness but more reliable in isolation.
 - Established 3 kV between layers, so space the conductors with layer separation or off-set the trace layout by 1 mm (40 mils).
 - Trace thickness is dependent on surge currents.
 - 0.3 mm on 1oz copper is a good safety factor for Ethernet & PoE.
 - 0.13 mm traces typically failed GR-1089-CORE Intra-building.

Closing Statement



Ethernet & PoE reminds me of the comments on some of my term school reports.....

Making progress, but must try harder!



Questions?



